

ABSTRACT OF THE DISCLOSURE

In a method of evaluating a piezoelectric field, a non-destructive spectrometry of piezoelectric fields is performed in a semiconductor heterojunction using a technique different from PR spectroscopy. In the method, at first, first and second absorption spectra are measured by irradiating infrared light to a sample with first and second angles, respectively. Then, a peak position of an absorption band having incident-angle dependent intensity is specified based on the first and second absorption spectra. Thus, the piezoelectric field strength is obtained based on an equation of energy level. The equation represents a relationship between the piezoelectric field and an electron energy level corresponding to the peak position.